Application/Control No.	Applicant(s)/Patent under Reexamination
10/532,582	CHEN ET AL.
Examiner	Art Unit
DON N. VO	2611

	SEARCHED						
Class	Subclass	Date	Examiner				
375	222, 285, 295, 296	8/9/2006	DV				
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INI	INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner				
375	295	8/10/2006	DV				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
		DATE	EXMR		
EAST		8/9/2006	DV		
		-			